

Search Notes

Application/Control No.

10/576,634

Examiner

BIN SHEN

Applicant(s)/Patent under
Reexamination

SANDERS ET AL.

Art Unit

1657

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR